

## Electrical Characteristics

$T_A = 25^\circ\text{C}$  unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
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### Off Characteristics

$BV_{DSS}$	Drain–Source Breakdown Voltage	$V_{GS} = 0\text{ V}, I_D = 250\ \mu\text{A}$	30			V
$\frac{\Delta BV_{DSS}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = 250\ \mu\text{A}$ , Referenced to $25^\circ\text{C}$		25		mV/ $^\circ\text{C}$
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = 24\text{ V}, V_{GS} = 0\text{ V}$			10	$\mu\text{A}$
$I_{GSS}$	Gate–Body Leakage	$V_{GS} = \pm 20\text{ V}, V_{DS} = 0\text{ V}$			$\pm 100$	nA

### On Characteristics (Note 2)

$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = 250\ \mu\text{A}$	1	2	3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate Threshold Voltage Temperature Coefficient	$I_D = 250\ \mu\text{A}$ , Referenced to $25^\circ\text{C}$		-5.6		mV/ $^\circ\text{C}$
$R_{DS(on)}$	Static Drain–Source On Resistance	$V_{GS} = 10\text{ V}, I_D = 12.5\text{ A}$ $V_{GS} = 4.5\text{ V}, I_D = 11\text{ A}$ $V_{GS} = 10\text{ V}, I_D = 12.5\text{ A}, T_J = 125^\circ\text{C}$		7.4 9.5 9	9 12 16	m $\Omega$
$g_{FS}$	Forward Transconductance	$V_{DS} = 10\text{ V}, I_D = 12.5\text{ A}$		48.4		S

### Dynamic Characteristics

$C_{iss}$	Input Capacitance	$V_{DS} = 15\text{ V}, V_{GS} = 0\text{ V},$		1444		pF
$C_{oss}$	Output Capacitance	$f = 1.0\text{ MHz}$		342		pF
$C_{rss}$	Reverse Transfer Capacitance			135		pF
$R_G$	Gate Resistance	$V_{GS} = 15\text{ mV}, f = 1.0\text{ MHz}$		1.25		$\Omega$

### Switching Characteristics (Note 2)

$t_{d(on)}$	Turn–On Delay Time	$V_{DD} = 15\text{ V}, I_D = 1\text{ A},$		10	20	ns
$t_r$	Turn–On Rise Time	$V_{GS} = 10\text{ V}, R_{GEN} = 6\ \Omega$		3.8	7.6	ns
$t_{d(off)}$	Turn–Off Delay Time			26	42	ns
$t_f$	Turn–Off Fall Time			13	23	ns
$Q_g$	Total Gate Charge	$V_{DS} = 15\text{ V}, I_D = 12.5\text{ A},$		14	20	nC
$Q_{gs}$	Gate–Source Charge	$V_{GS} = 5\text{ V}$		4		nC
$Q_{gd}$	Gate–Drain Charge			5		nC

### Drain–Source Diode Characteristics and Maximum Ratings

$I_S$	Maximum Continuous Drain–Source Diode Forward Current				1.5	A
$V_{SD}$	Drain–Source Diode Forward Voltage	$V_{GS} = 0\text{ V}, I_S = 1.5\text{ A}$ (Note 2)		0.73	1.2	V
$t_{rr}$	Diode Reverse Recovery Time	$I_F = 12.5\text{ A},$		25		nS
$Q_{rr}$	Diode Reverse Recovery Charge	$d_{IF}/d_t = 100\text{ A}/\mu\text{s}$		15		nC

**Notes:** 1.  $R_{\theta JA}$  is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{\theta JC}$  is guaranteed by design while  $R_{\theta CA}$  is determined by the user's board design.



a)  $60^\circ\text{C/W}$  when mounted on a  $1\text{ in}^2$  pad of 2 oz copper



b)  $111^\circ\text{C/W}$  when mounted on a minimum pad of 2 oz copper

Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width <  $300\ \mu\text{s}$ , Duty Cycle < 2.0%

## Typical Characteristics

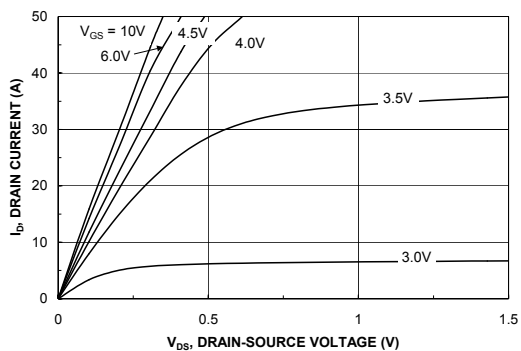


Figure 1. On-Region Characteristics.

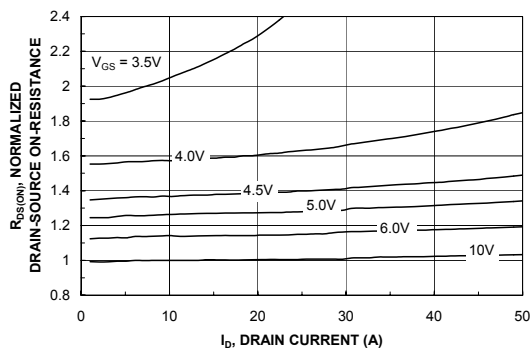


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

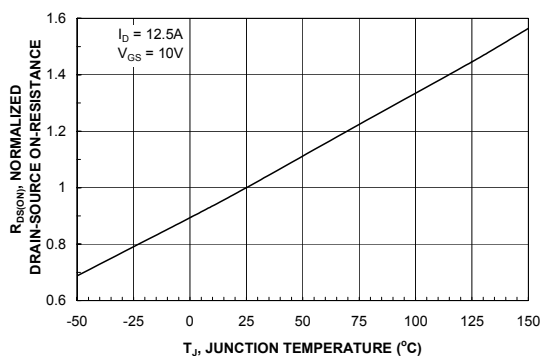


Figure 3. On-Resistance Variation with Temperature.

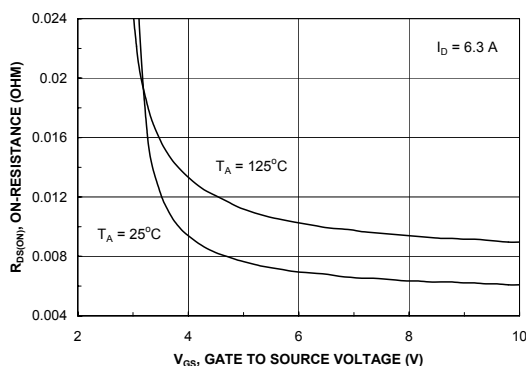


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

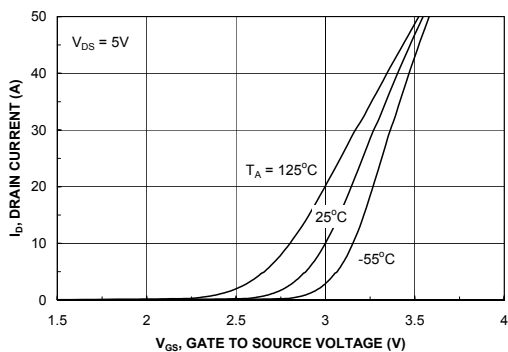


Figure 5. Transfer Characteristics.

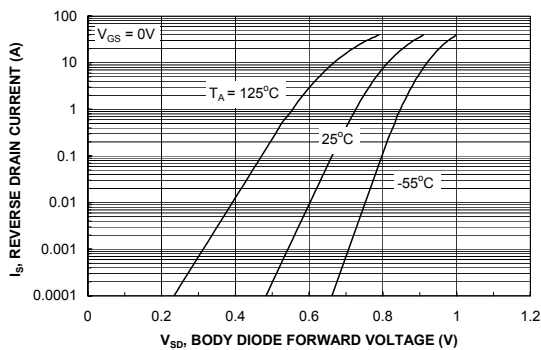


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

## Typical Characteristics

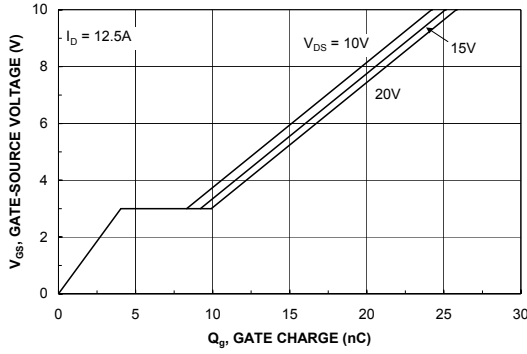


Figure 7. Gate Charge Characteristics.

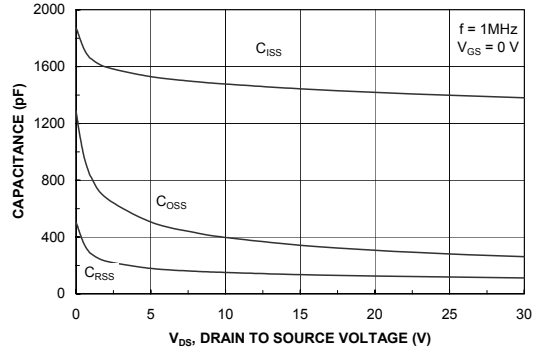


Figure 8. Capacitance Characteristics.

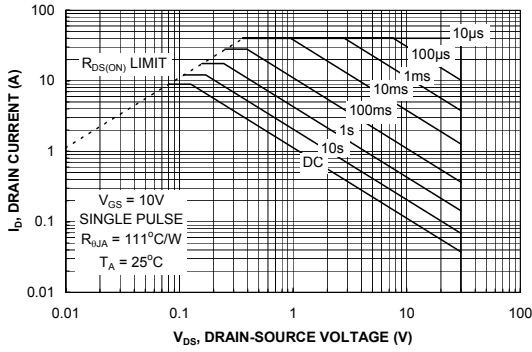


Figure 9. Maximum Safe Operating Area.

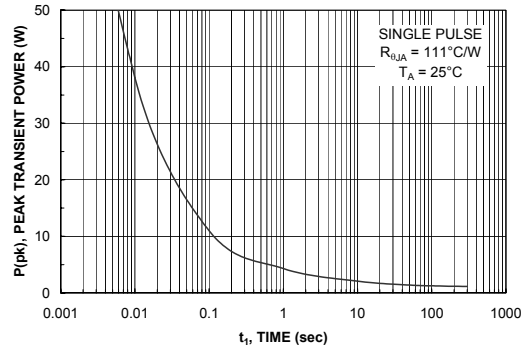


Figure 10. Single Pulse Maximum Power Dissipation.

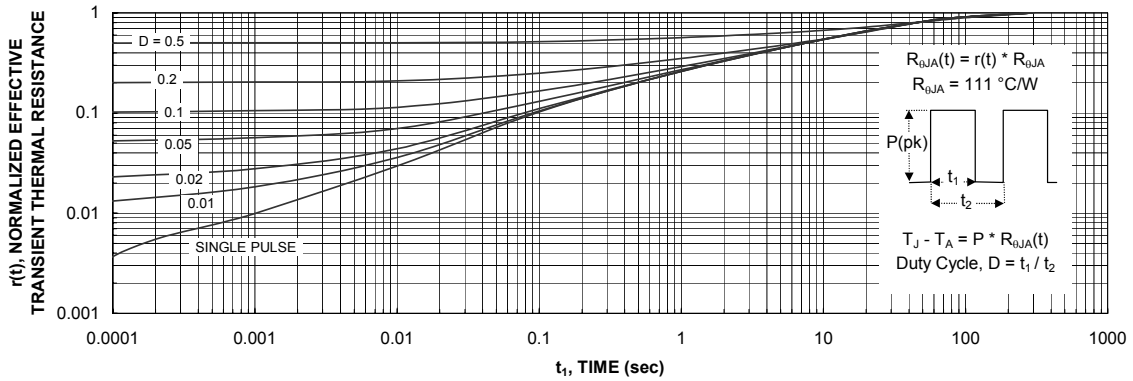
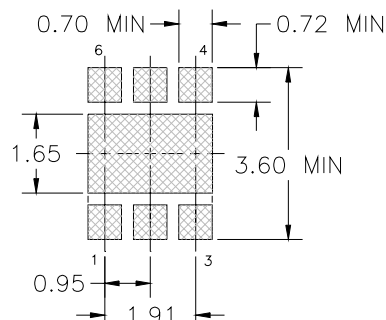
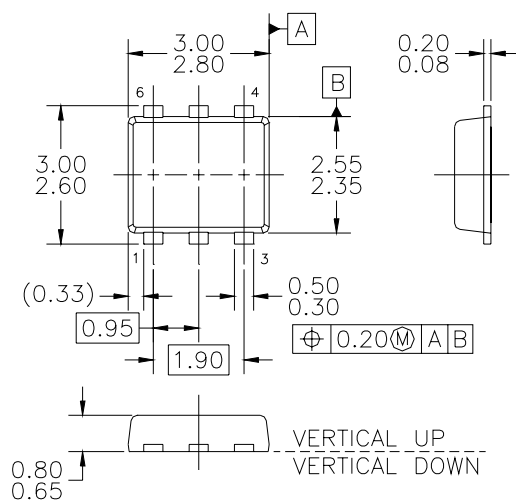


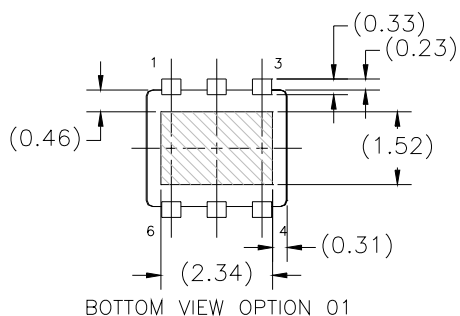
Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1c. Transient thermal response will change depending on the circuit board design.

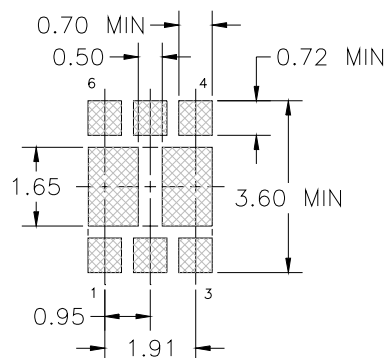
### Dimensional Outline and Pad Layout



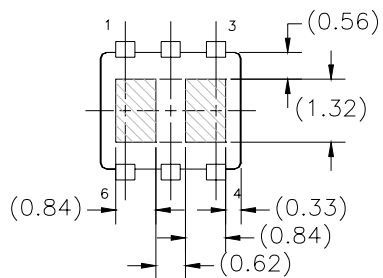
LAND PATTERN RECOMMENDATION (OPTION 01)



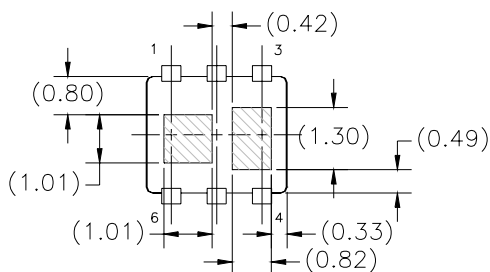
BOTTOM VIEW OPTION 01



LAND PATTERN RECOMMENDATION (OPTION 02&03)



BOTTOM VIEW OPTION 02



BOTTOM VIEW OPTION 03

NOTES: UNLESS OTHERWISE SPECIFIED

- A) NO PACKAGE STANDARD REFERENCE AS OF MARCH, 2001.
- B) ALL DIMENSIONS ARE IN MILLIMETERS.
- C) DIMENSIONS DO NOT INCLUDE MOLD FLASH AND CUTTING BURRS.
- D) LEAD TIP BURR:  
 HORIZONTAL: 0.20 mm MAX  
 VERTICAL UP: 0.20 mm MAX  
 VERTICAL DOWN: 0.05 mm MAX

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CROSSVOLT™	FRFET™	MicroPak™	QFET®	SuperSOT™-8
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